

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/051,631	VASUDEVAN ET AL.	
	Examiner Sy D Luu	Art Unit 2174	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0114904 A1	06-2004	Sun et al.	386/046
*	B	US-5,550,965	08-1996	Gabbe et al.	715/512
*	C	US-5,642,171	06-1997	Baumgartner et al.	348/515
*	D	US-5,949,410	09-1999	Fung, Hei Tao	715/500.1
*	E	US-6,122,668	09-2000	Teng et al.	709/231
*	F	US-6,369,835	04-2002	Lin, Tony Hongtong	345/726
*	G	US-6,404,978	06-2002	Abe, Keiko	386/55
*	H	US-6,504,990	01-2003	Abecassis, Max	386/46
*	I	US-6,616,700	09-2003	Thum et al.	715/500.1
*	J	US-6,621,502	09-2003	Nair et al.	345/716
*	K	US-6,636,237	10-2003	Murray et al.	345/719
*	L	US-6,636,238	10-2003	Amir et al.	345/730
*	M	US-6,738,075	05-2004	Torres et al.	345/723

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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